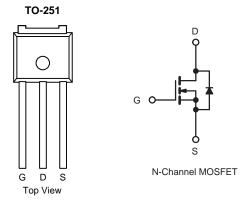


N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A)	Q _g (Typ.)		
30	0.07 at V _{GS} = 10 V	53	19 nC		
	0.09 at V _{GS} = 4.5 V	48	19110		



FEATURES

- Halogen-free
- TrenchFET® Gen III Power MOSFET
- 100 % R_g Tested 100 % UIS Tested

APPLICATIONS

- DC/DC Conversion
 - System Power

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	30	V	
Gate-Source Voltage		V_{GS}	± 20		
Continuous Drain Current (T _J = 150 °C)	$T_{C} = 25 ^{\circ}\text{C}$ $T_{C} = 70 ^{\circ}\text{C}$ $T_{A} = 25 ^{\circ}\text{C}$ $T_{A} = 70 ^{\circ}\text{C}$	I _D	53 41 14 ^{b, c} 10 ^{b, c}	A	
Pulsed Drain Current		I _{DM}	165		
Avalanche Current Avalanche Energy	L = 0.1 mH	I _{AS}	25 40	mJ	
Continuous Source-Drain Diode Current $\frac{T_C = 25 \text{ °C}}{T_A = 25 \text{ °C}}$		I _S	15 2.9 ^{b, c}	A	
Maximum Power Dissipation	$T_C = 25 ^{\circ}\text{C}$ $T_C = 70 ^{\circ}\text{C}$ $T_A = 25 ^{\circ}\text{C}$	P _D	28 18 3.5 ^{b, c}	w	
T _A = 70 °C		T T	2.2 ^{b, c}		
Operating Junction and Storage Temperature Range Soldering Recommendations (Peak Temperature)		T _J , T _{stg}	- 55 to 150 260	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient	t ≤ 10 s	R _{thJA}	29	36	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	R_{thJC}	3.6	4.5	O/ VV	

- a. Based on T_C = 25 °C.
 b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.



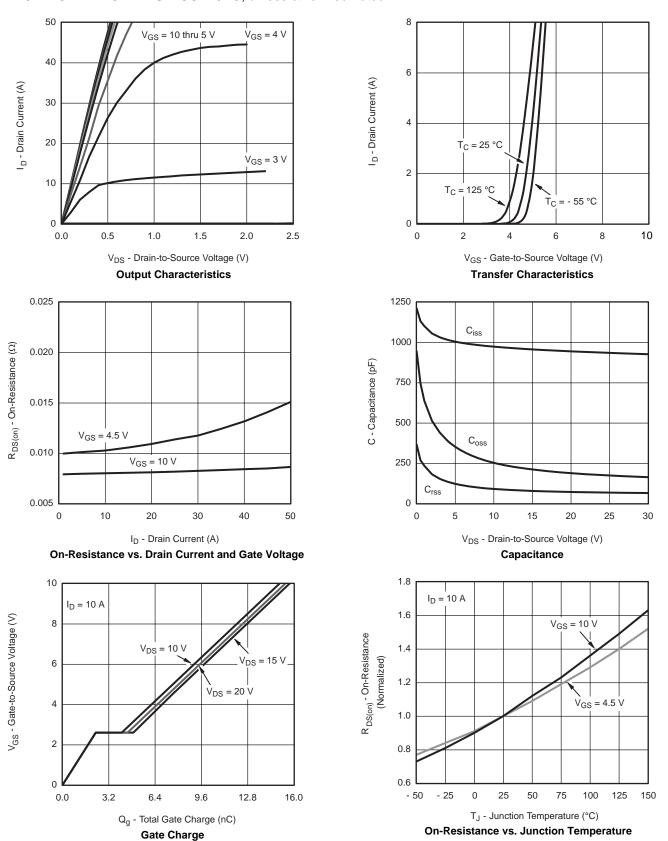
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		33		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	I _D = 250 μA		- 5		mv/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu A$	1.2		3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zana Oata Waltana Busin Oamani		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			5		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	15			Α	
D : 0		$V_{GS} = 10 \text{ V}, I_{D} = 10 \text{ A}$		0.070		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_{D} = 7 \text{ A}$		0.090			
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 10 A		24		S	
Dynamic ^b						l	
Input Capacitance	C _{iss}			1400			
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		200		pF	
Reverse Transfer Capacitance	C _{rss}			150			
Total Gate Charge	Qg	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 10 \text{ A}$		33		nC	
				18			
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$		7.3			
Gate-Drain Charge	Q_{gd}			6.2			
Gate Resistance	R_g	f = 1 MHz	0.2	0.8	1.6	Ω	
Turn-On Delay Time	t _{d(on)}			15	30	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.5 Ω		12	24		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		13	26		
Fall Time	t _f			10	20		
Turn-On Delay Time	t _{d(on)}			9	18		
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 1.5 \Omega$		9	18		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 10$ A, $V_{GEN}=10$ V, $R_g=1$ Ω		14	28		
Fall Time	t _f			8	16		
Drain-Source Body Diode Characteristi	cs						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			16	Λ.	
Pulse Diode Forward Current	I _{SM}				32	Α	
Body Diode Voltage	V _{SD}	I _S = 3 A, V _{GS} = 0 V		0.78	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			17	34	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 10 A, dI/dt = 100 A/μs, T _{.I} = 25 °C		9.5	19	nC	
Reverse Recovery Fall Time	t _a	$I_F = 10 \text{ A}$, $\alpha I/\alpha I = 100 \text{ A}/\mu \text{ S}$, $I_J = 25 ^{\circ}\text{C}$		10			
Reverse Recovery Rise Time	t _b	_		7		ns	

Notes:

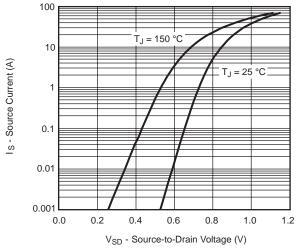
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

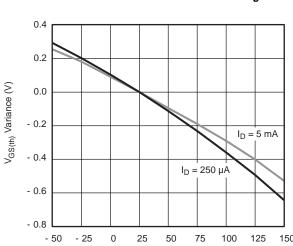






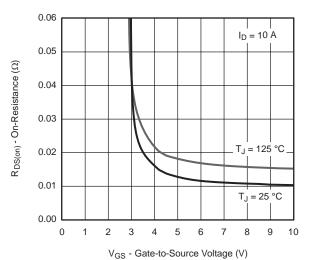


Source-Drain Diode Forward Voltage

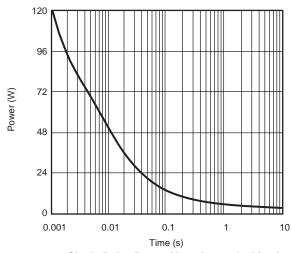


T_J - Temperature (°C)

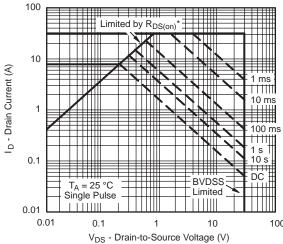
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage



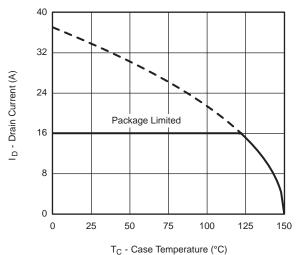
Single Pulse Power (Junction-to-Ambient)



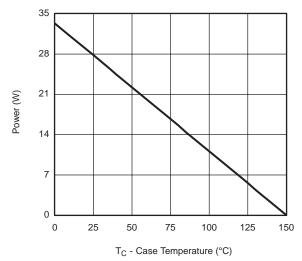
* V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified

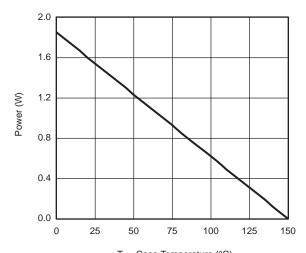
Safe Operating Area, Junction-to-Ambient





Current Derating*





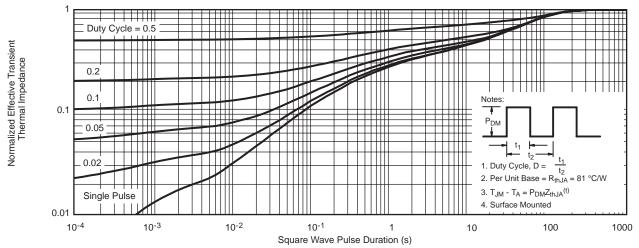
T_A - Case Temperature (°C)

Power, Junction-to-Case

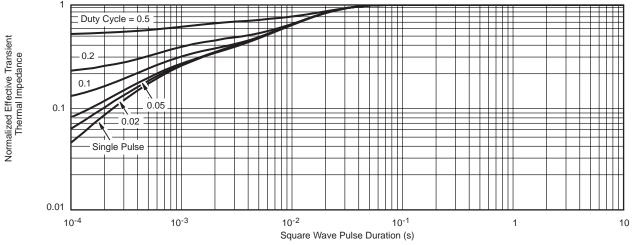
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





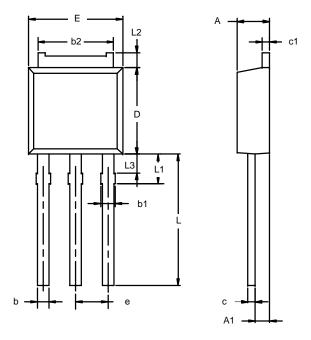
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



TO-251AA (DPAK)



Note:	Dimension	L3 is for	reference only.
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	MILLIM	IETERS	INC	HES	
Dim	Min	Max	Min	Max	
Α	2.21	2.38	0.087	0.094	
A 1	0.89	1.14	0.035	0.045	
b	0.71	0.89	0.028	0.035	
b1	0.76	1.14	0.030	0.045	
b2	5.23	5.43	0.206	0.214	
С	0.46	0.58	0.018	0.023	
с1	0.46	0.58	0.018	0.023	
D	5.97	6.22	0.235	0.245	
Е	6.48	6.73	0.255	0.265	
е	2.28	BSC	0.090 BSC		
L	3.89	9.53	0.153	0.375	
L1	1.91	2.28	0.075	0.090	
L2	0.89	1.27	0.035	0.050	
L3	1.15	1.52	0.045	0.060	
ECN: S-03946—Rev. E, 09-Jul-01 DWG: 5346					



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